

INTERNATIONAL STANDARD



**Semiconductor devices –
Part 5-9: Optoelectronic devices – Light emitting diodes – Test method of the
internal quantum efficiency based on the temperature-dependent
electroluminescence**



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CONTENTS

FOREWORD.....	3
1 Scope.....	5
2 Normative references	5
3 Terms, definitions and abbreviated terms	5
3.1 Terms and definitions.....	5
3.2 Abbreviated terms.....	7
4 Measuring methods	7
4.1 Basic requirements	7
4.1.1 Measuring conditions.....	7
4.1.2 Measuring instruments and equipment.....	7
4.2 Purpose	7
4.3 Measurement.....	8
4.3.1 Measurement setup	8
4.3.2 Measurement principle.....	8
4.3.3 Measurement sequence.....	11
5 Test report.....	12
Annex A (informative) Test examples.....	13
A.1 Test example (category 1)	13
A.2 Test example (category 2)	16
Bibliography.....	19
Figure 1 – Example of the measurement setup with the TDEL.....	8
Figure 2 – Schematic diagram of radiant power as a function of forward current at various temperatures	9
Figure 3 – Examples of relative EQEs showing whether the IQE is measurable or not	10
Figure 4 – IQE measurement with TDEL.....	10
Figure 5 – Sequence of IQE determination with TDEL.....	12
Figure A.1 – Radiant power as a function of forward current at various temperatures (category 1)	13
Figure A.2 – Relative EQE as a function of forward current at various temperatures (category 1)	14
Figure A.3 – Check T_C in relative EQE curves (category 1)	14
Figure A.4 – Evaluation of the relative EQE (category 1).....	15
Figure A.5 – IQE as a function of forward current at various temperatures including an operating temperature (category 1).....	15
Figure A.6 – Radiant power as a function of forward current at various temperatures (category 2)	16
Figure A.7 – Relative EQE as a function of forward current at various temperatures (category 2)	17
Figure A.8 – Check T_C in relative EQE curves (category 2)	17
Table A.1 – Summary of test report.....	18

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The text of this International Standard is based on the following documents:

CDV	Report on voting
47E/651/CDV	47E/676/RVC

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 60747 series, published under the general title *Semiconductor devices*, can be found on the IEC website.

Future standards in this series will carry the new general title as cited above. Titles of existing standards in this series will be updated at the time of the next edition.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

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SEMICONDUCTOR DEVICES –

Part 5-9: Optoelectronic devices – Light emitting diodes – Test method of the internal quantum efficiency based on the temperature-dependent electroluminescence

1 Scope

This part of IEC 60747 specifies the measuring method of the internal quantum efficiency (IQE) of single light emitting diode (LED) chips or packages without phosphor. White LEDs for lighting applications are out of the scope of this document. This document utilizes the relative external quantum efficiencies (EQEs) measured at cryogenic temperatures and at an operating temperature, which is called temperature-dependent electroluminescence (TDEL). In order to identify the reference IQE of 100 %, the maximum values of the peak EQE are found by varying the environmental temperature and current.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60747-5-6:2016, *Semiconductor devices – Part 5-6: Optoelectronic devices – Light emitting diodes*

3 Terms, definitions and abbreviated terms

3.1 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>

3.1.1

radiant power

Φ_e

power emitted, transmitted or received in the form of radiation

Note 1 to entry: The unit used is: W. Radiant power is also known as the "radiant flux".

[SOURCE: IEC 60747-5-8:2019, 3.1.1]

3.1.2

internal quantum efficiency

η_{IQE}

ratio of the number of photons emitted from the active region per unit time to the number of electrons injected into the LED per unit time